History			
1970s •	Hitachi High-Tech Science Corporate History 1970 Daini Seikosha, current Seiko Instruments Inc., established an R&D Center and entered into the business of scientific instruments	Hitachi High-Tech Science SPM Product History	History of SPM
1980s •		 1985 STM research & development with the National Institute of Advanced Industrial Science and Technology (AIST) 1986 First AFM observation (NbSe₂) in Japan by AIST Image: State of Advanced Industrial Science and Technology (AIST) 1986 Commercialization of Japan's first STM (SAM2000) 	 1981 First STM observation of atoms by Dr. Binnig, Dr. Rohrer (IBM Zurich Laboratory) 1986 AFM development by Dr. Binnig (IBM), Dr. Quate (Stanford University) Dr. Binnig, Dr. Rohrer received the Noble Prize in Physics
1990s -		1991 Japan's first AFM (SFA300) 1992 Japan's first SPM (SPA300)	
2000s •	 2000 Seiko Instruments founded SII Microscope Inc. 2003 SII Microscope Inc. changed company name to SII NanoTechnology Inc. SII NanoTechnology succeeded the scientific instruments business of Seiko Instruments by partition of corporation 	Main unit: Controller: Nanocute SPI4000 S-image NanoNavi E-sweep NanoNaviⅡ L-trace L-traceⅡ	
2010s •-	 2013 Became a member of Hitachi High-Technologies Group and officially changed company name to Hitachi High-Tech Science Corporation. Company head office moved to Minato-ku, Tokyo Hitachi High-Tech Science succeeded Design & Development, QA and Domestic Sales section of analytical instruments business from Hitachi High-Technologies 	Main unit: Controller: AFM5100N AFM5000 AFM5200S (NanoNavi Real) AFM5300E AFM5000II AFM5400L	